



MUSE

MUSE General Meeting

Summary on QA of the Mu2e calorimeter SiPMs

MUSE General Meeting

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QA Procedure

- The tests successfully ended in June 2019.
- One batch is ~ 280 pieces. Delivery of one batch/month started from March 2018
- **First Step:** Visive inspection
- **Second Step:** Mechanical and dimensional check (100 μm tolerance)
- **Third Step:** Characterization
 - R1) a relative spread in V_{op} (operational voltage) between the sensor cells < 0.5%.
 - R2) a relative spread in the dark current at V_{op} between the sensor cells < 15%.
 - R3+R4) a gain x PDE(310 nm) at $V_{op} > 2 \cdot 10^5$ for each cell.

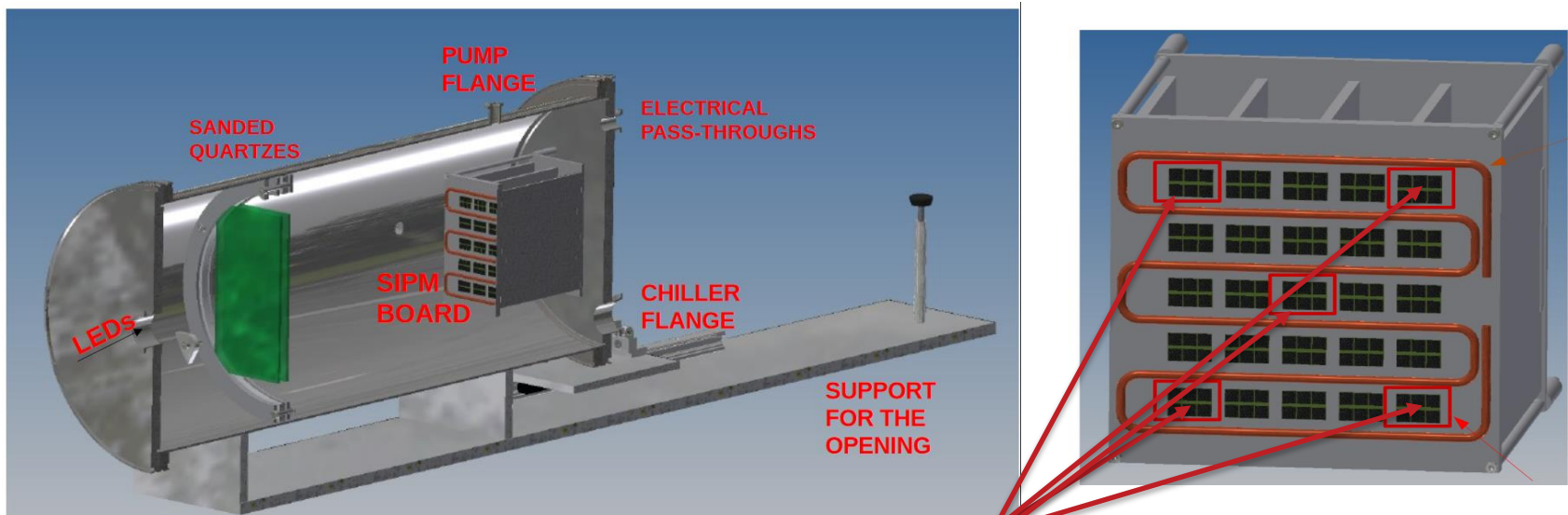


Sensors that didn't meet the requirements have been discarded.

- A random subset of 15 devices/batch is used to evaluate MTTF, while other 5 sensors/batch are used for neutron irradiation

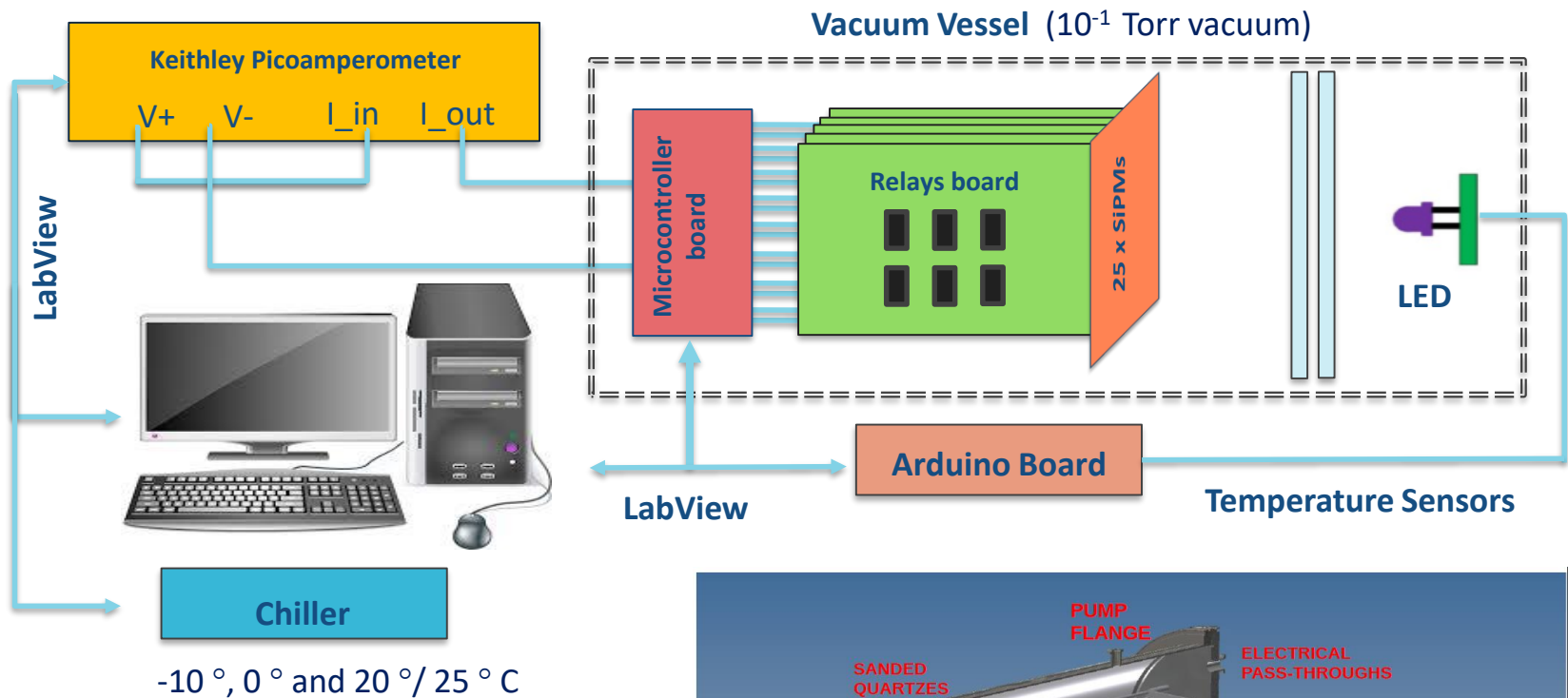
What are we measuring?

- QA required $4k \times 6 = 24k$ full characterizations -> automatized system
- Test station able to measure (1.2 mins/cell) at three temperatures (-10° , 0° and $20^\circ/25^\circ$ C):
 1. V_b – by fitting the I-V curve;
 2. I_{dark} @ V_{op} – directly by the I-V curve;
 3. **Gain x PDE @ V_{op}** – by the ratio of the currents pulled by the cell and a reference sensor, while illuminating both with a stable and uniform light;



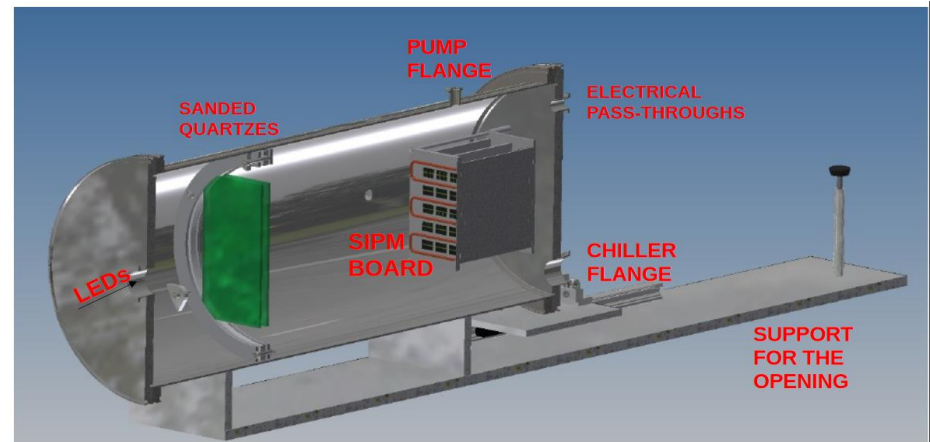
Reference Sensors

Experimental Setup for QA



For each cell we measure:

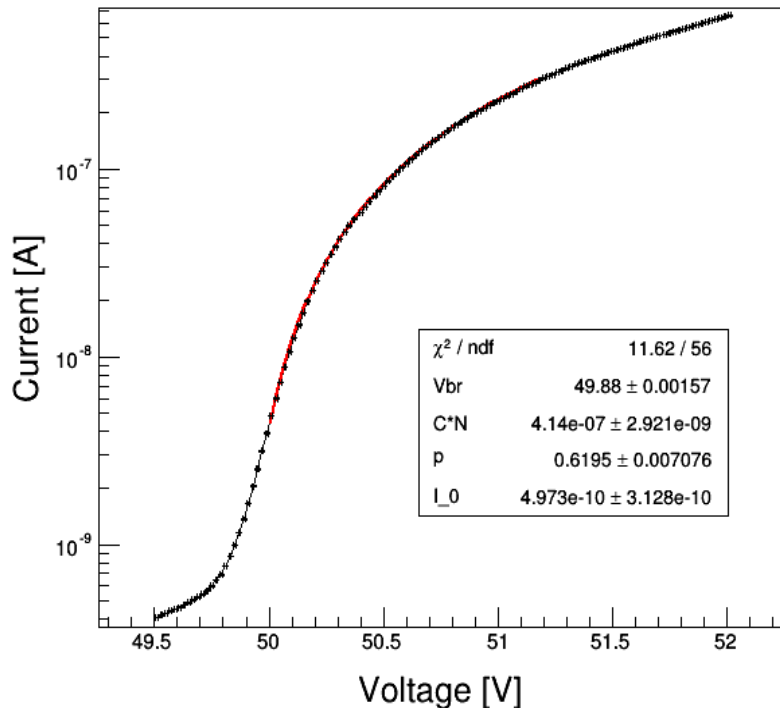
1. Breakdown Voltage
2. Dark Current @ V_{op}
3. Gain x PDE @ V_{op}



Measurement of Breakdown Voltage

- To extract the breakdown voltage, a 150 points voltage scan in a 2.5 V range is performed and the obtained curve is fitted with :

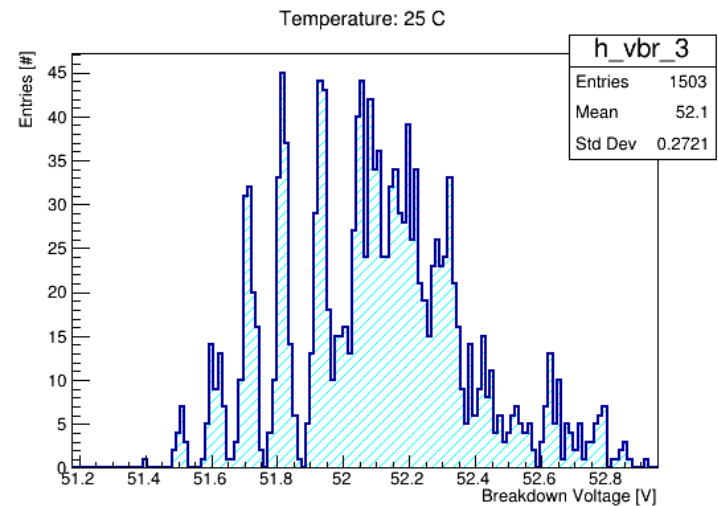
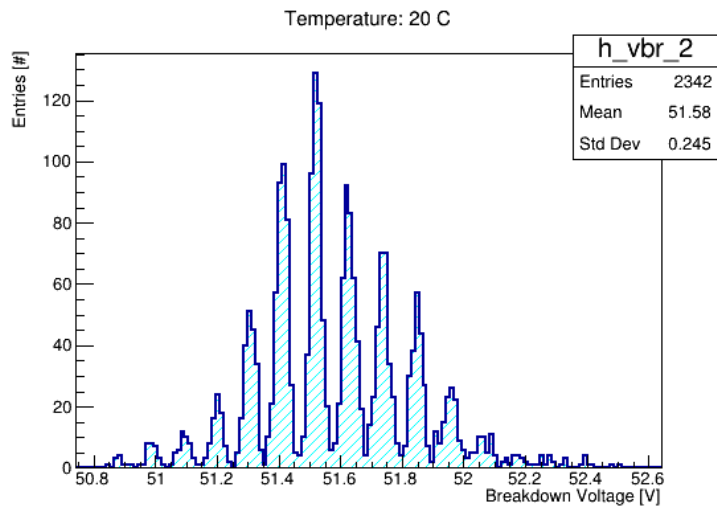
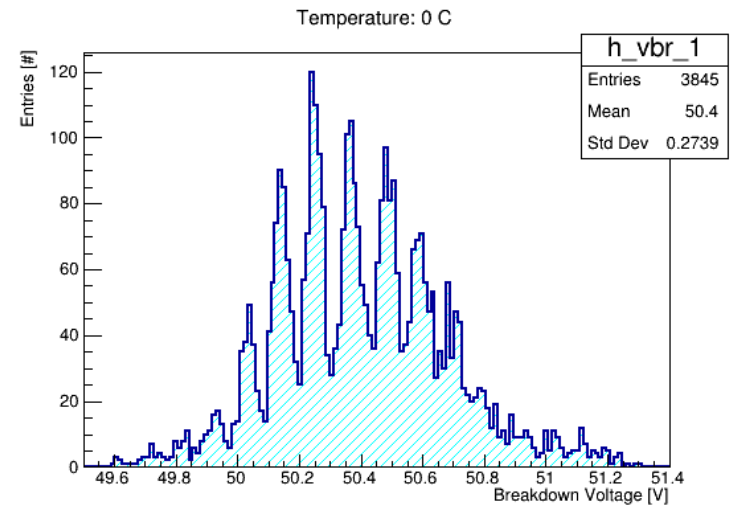
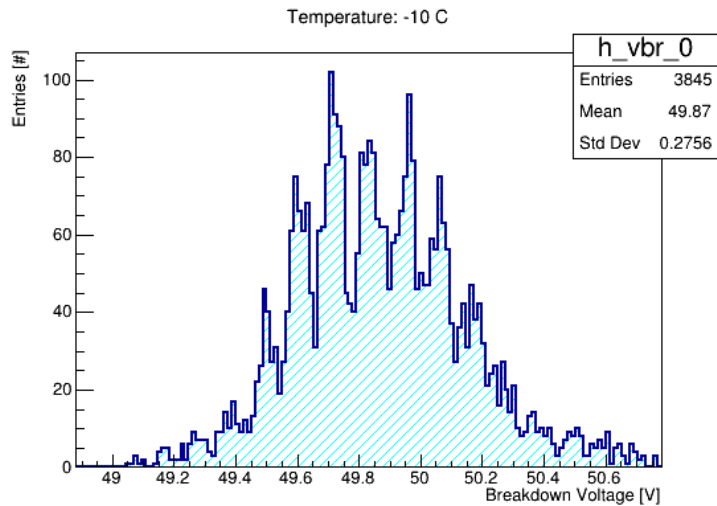
$$I(V) = \begin{cases} I_0 + C \times (1 - e^{-p \cdot (V - V_{br})}) \times (V - V_{br}) & V > V_{br} \\ I_0 & V < V_{br} \end{cases}$$



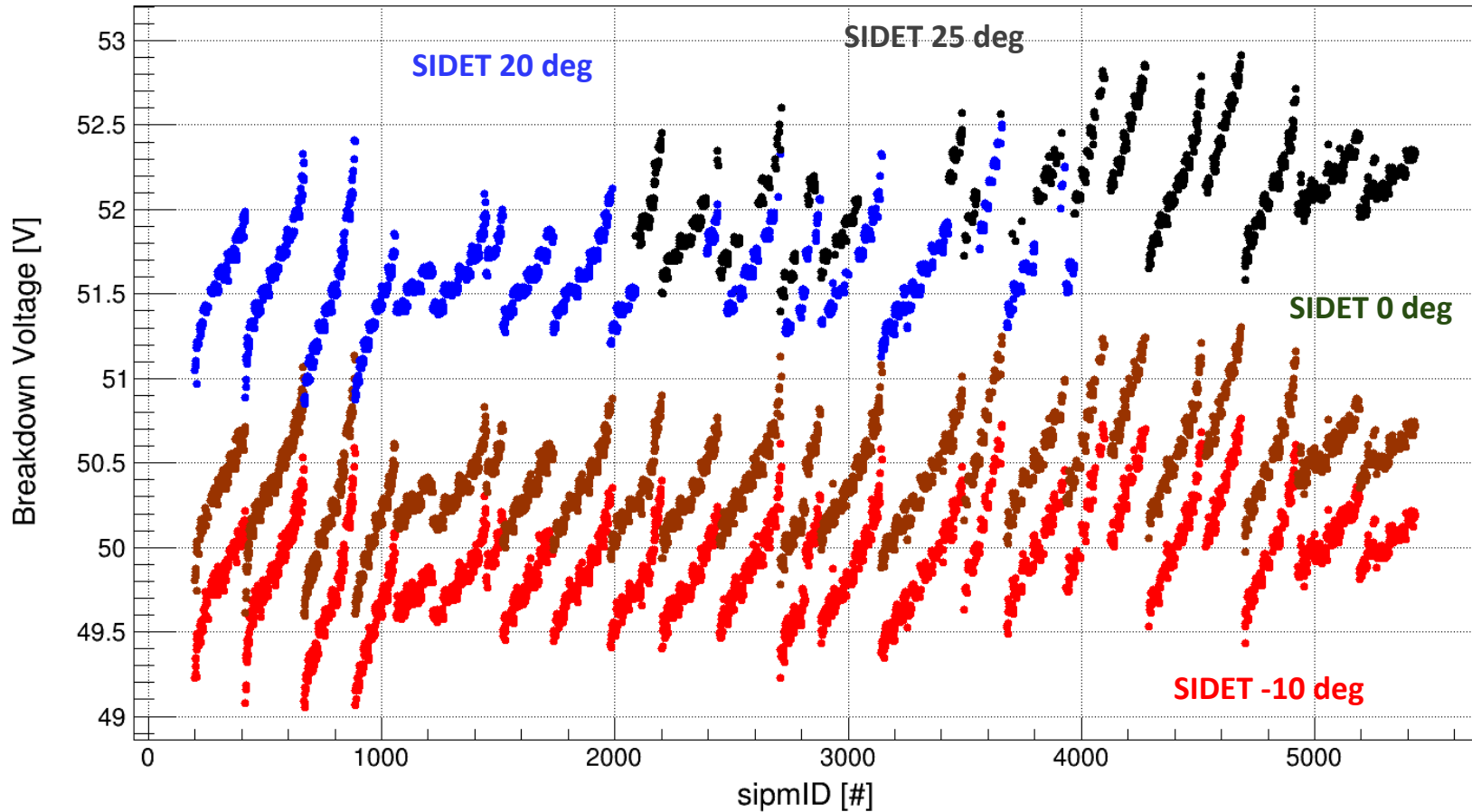
- Where:
 - V is the bias voltage
 - Vbr is the breakdown voltage
 - I₀ is the current before the breakdown
 - P is the Geiger probability
 - C is proportional to the number of the free carriers (thermal + optical)
- It is valid under 2 assumptions:
 - Afterpulse and crosstalk are negligible
 - We are far from the 'second breakdown' zone

A. Nagai, N. Dinu, A. Para , "Breakdown voltage and triggering probability of SiPM from IV curves"

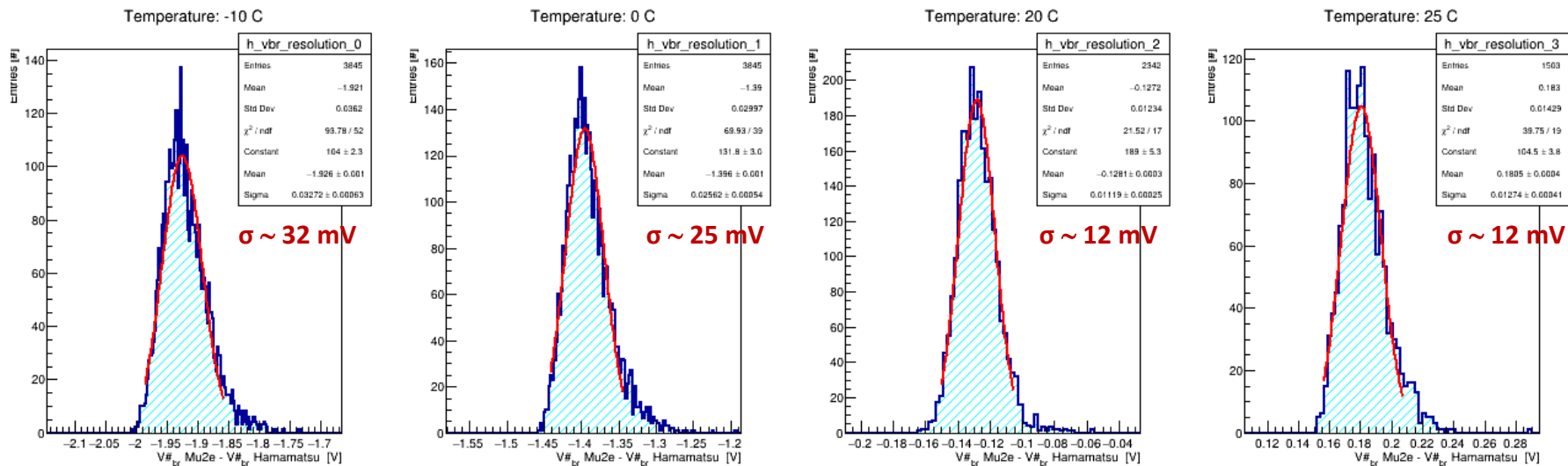
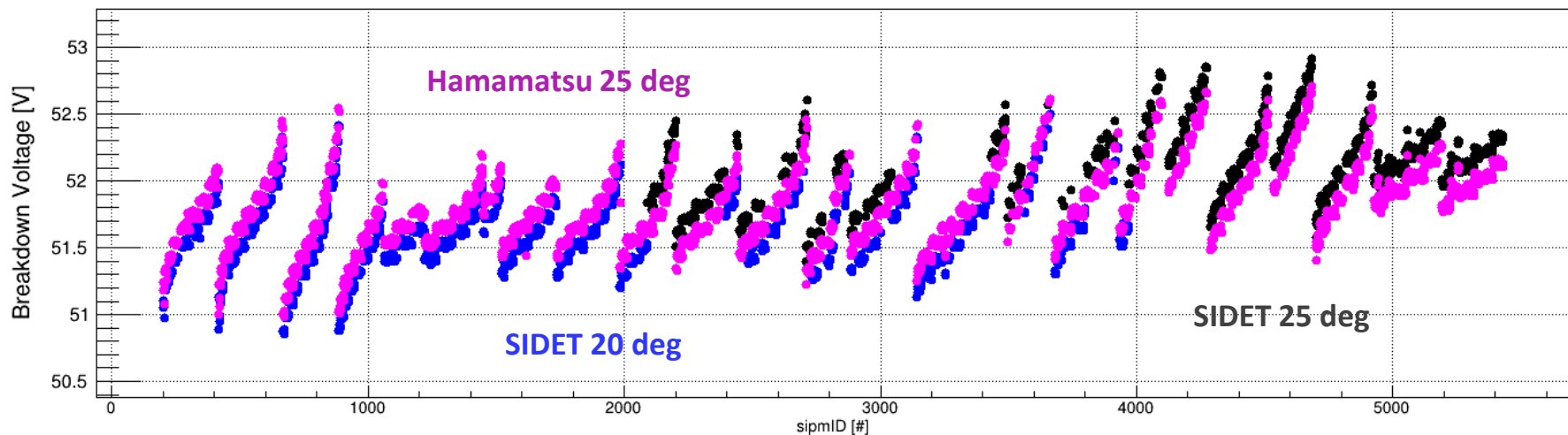
Distribution of the Breakdown Voltage



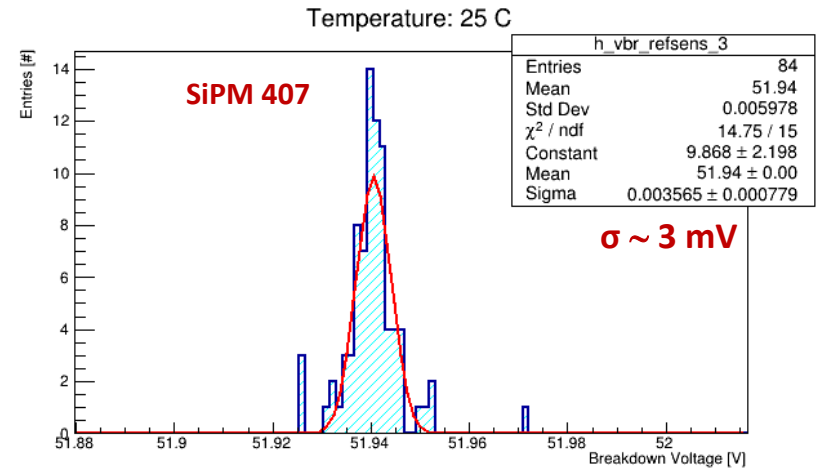
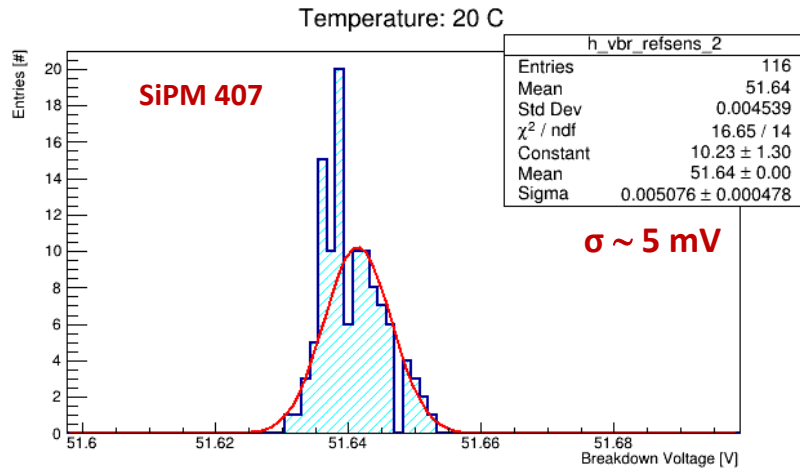
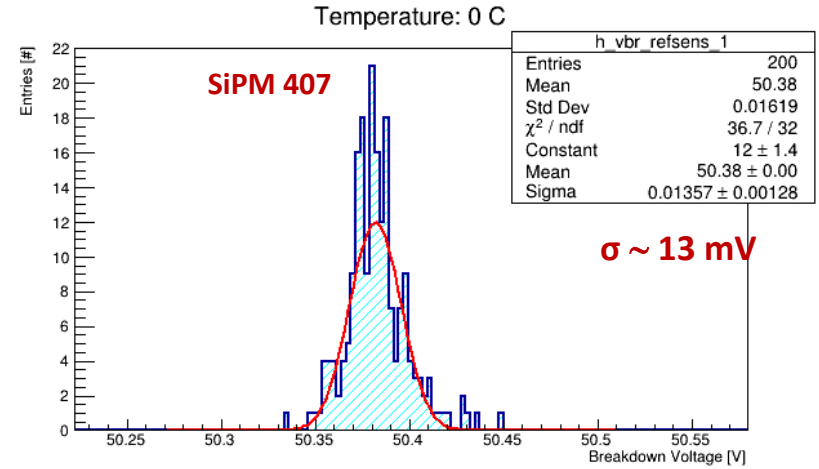
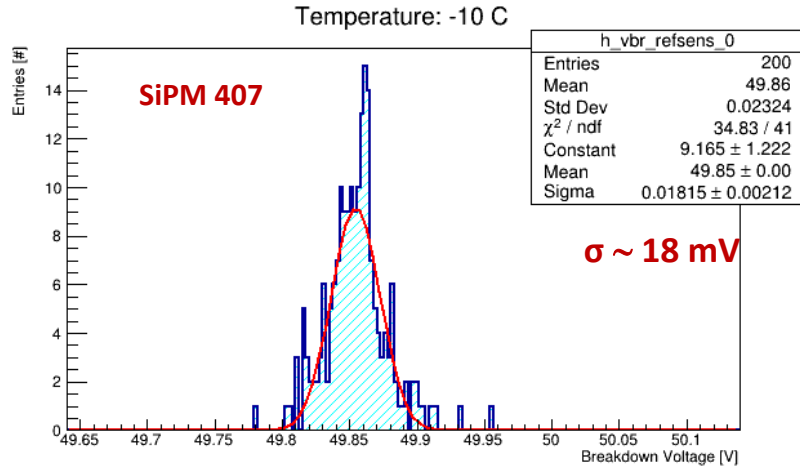
Breakdown Voltage Vs sipmID



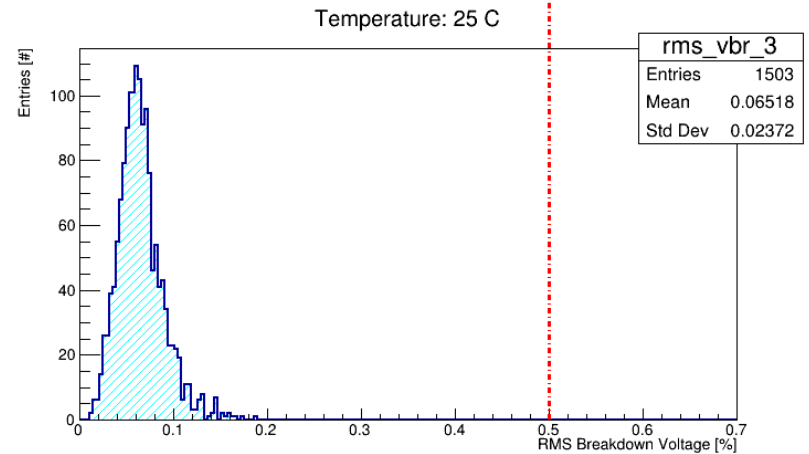
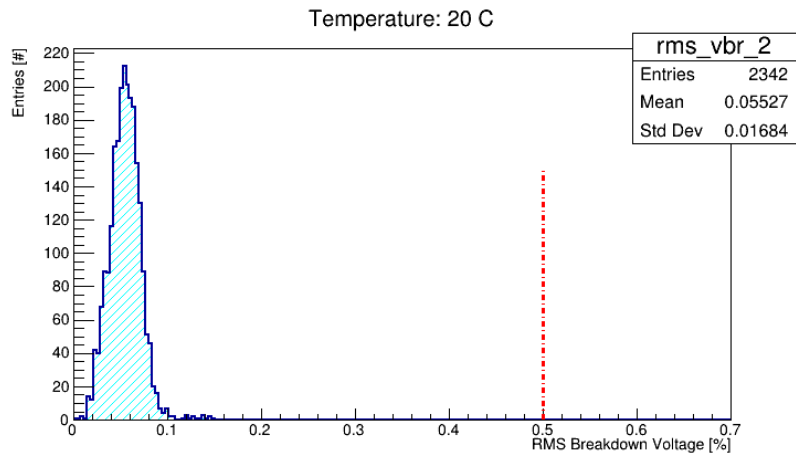
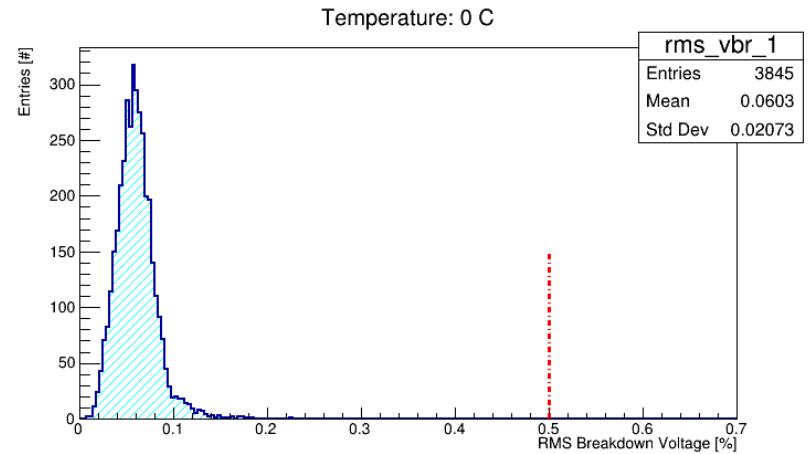
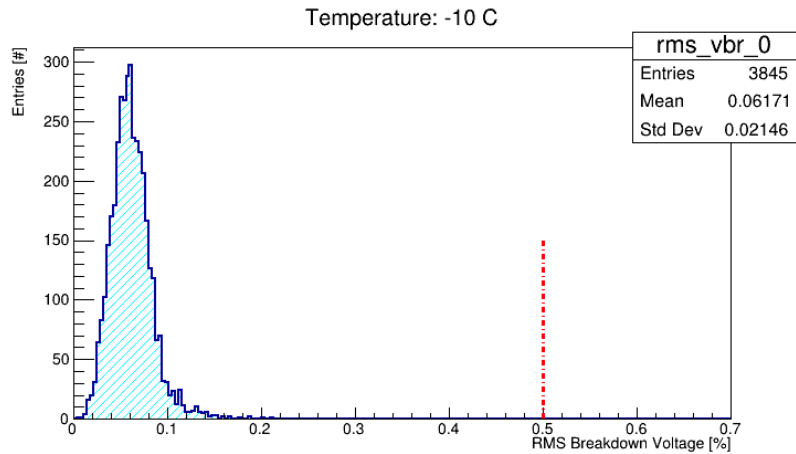
Comparison with Hamamatsu



Stability of Breakdown Voltage

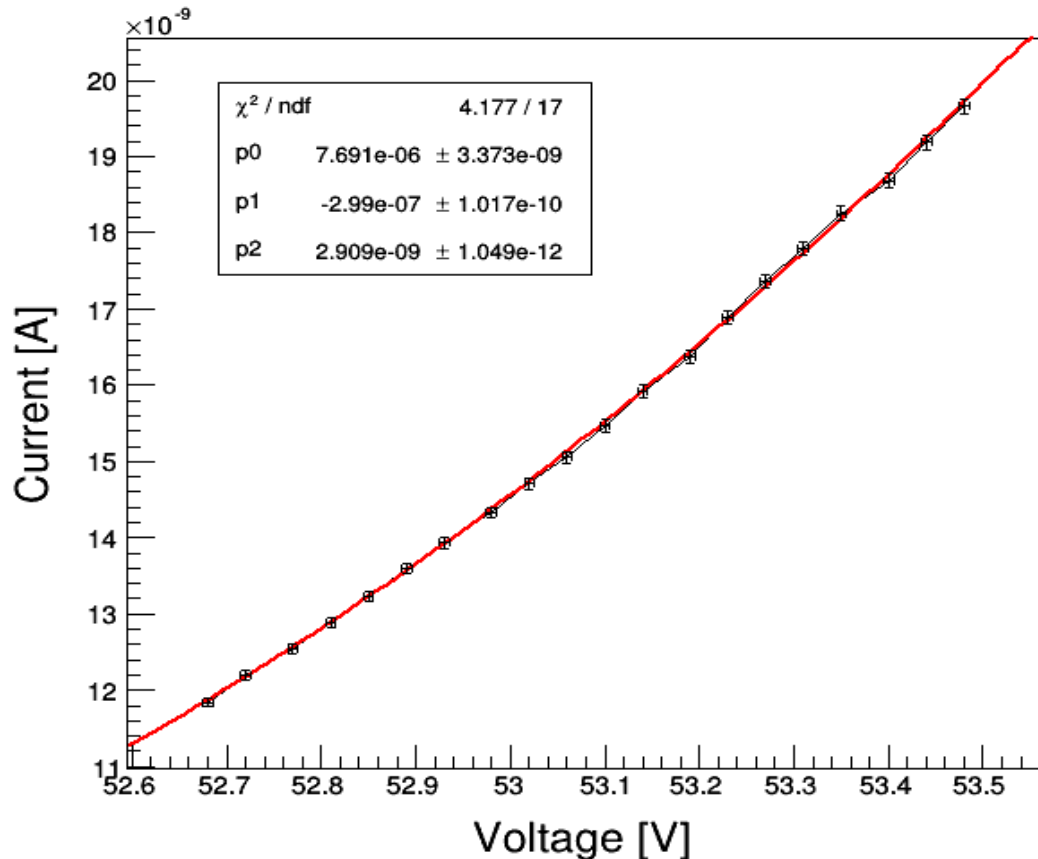


Breakdown Voltage RMS



Dark Current Measurement

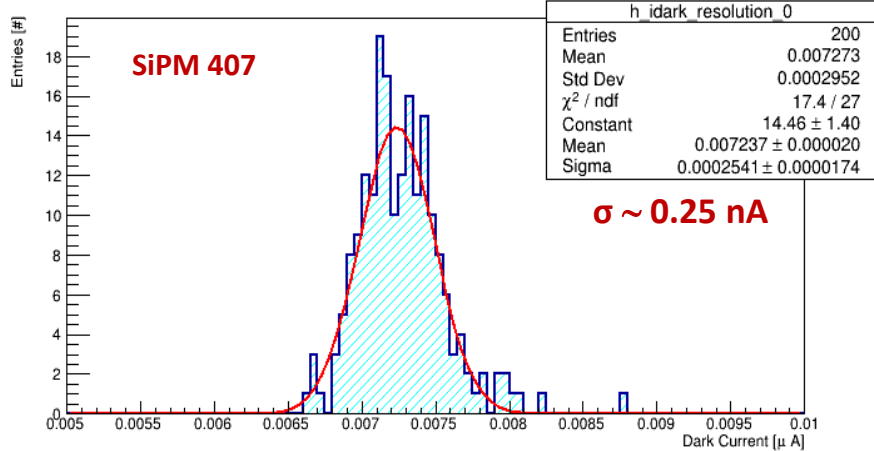
- The dark current measurement has been performed according to three steps:



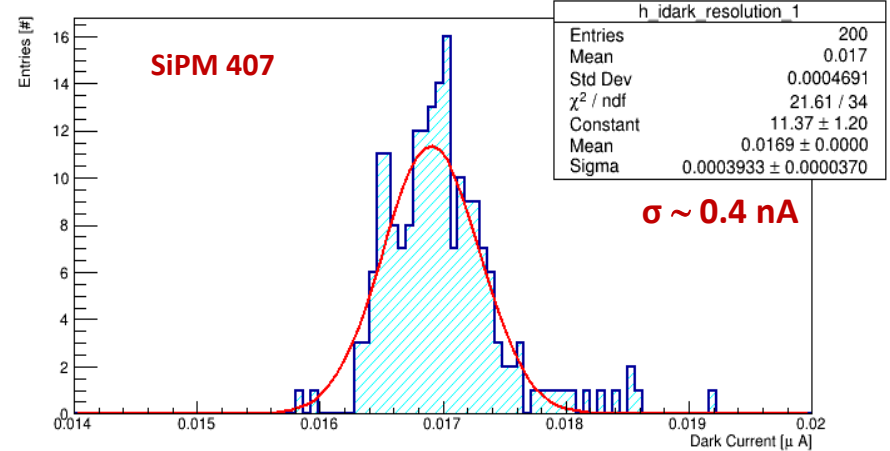
- A scan of 0.8 V around the peak of the $\text{dlog}(I)/\text{dV} + 3$ V is performed
- The current is fitted with a pol2
- The dark current is obtained by taking the value of the pol2 at the V_{br} extracted from the curve, corrected for temperature, +3

Stability of Dark Current

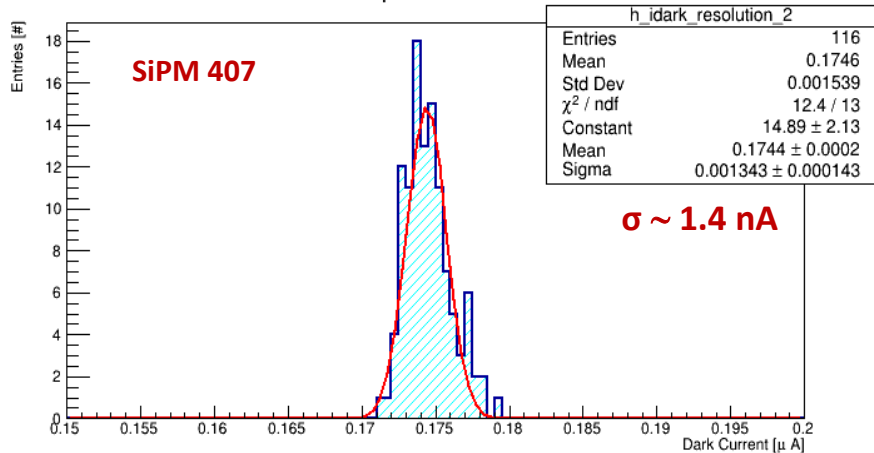
Temperature: -10 C



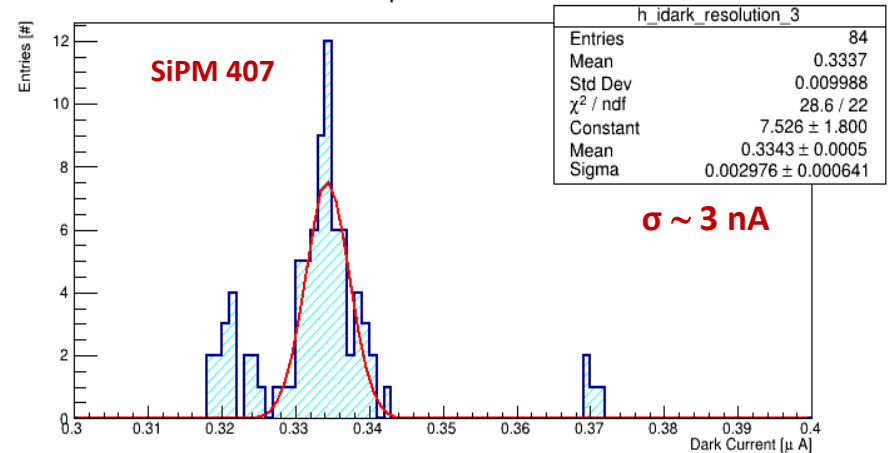
Temperature: 0 C



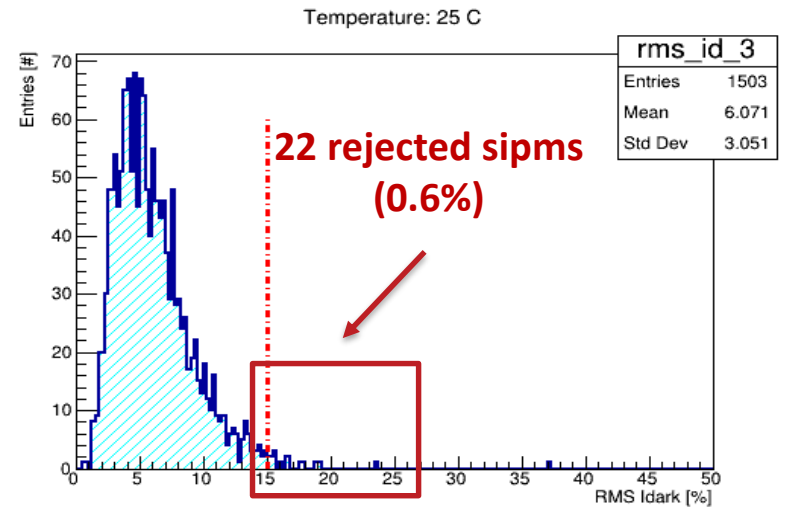
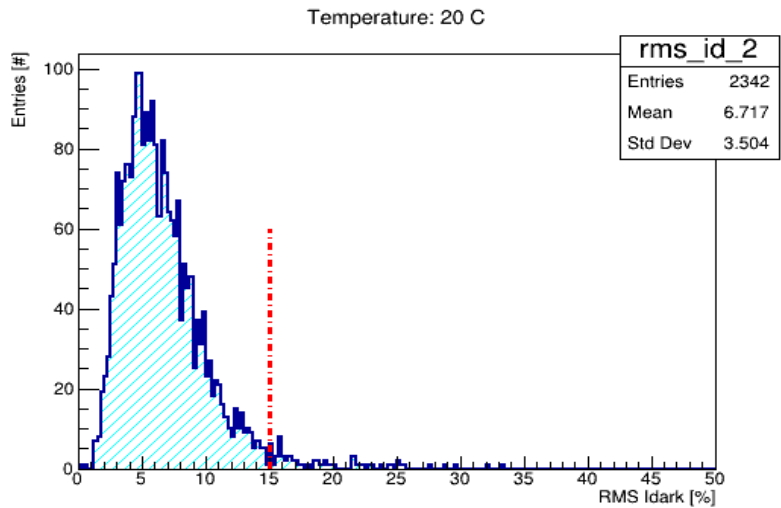
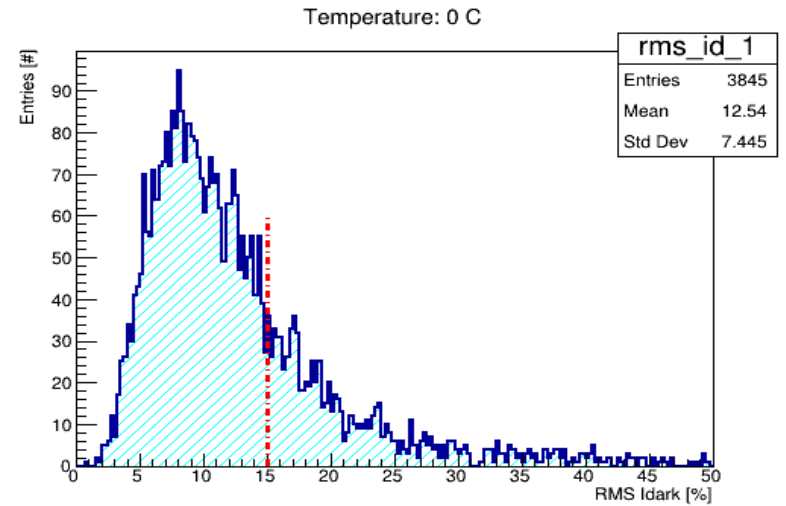
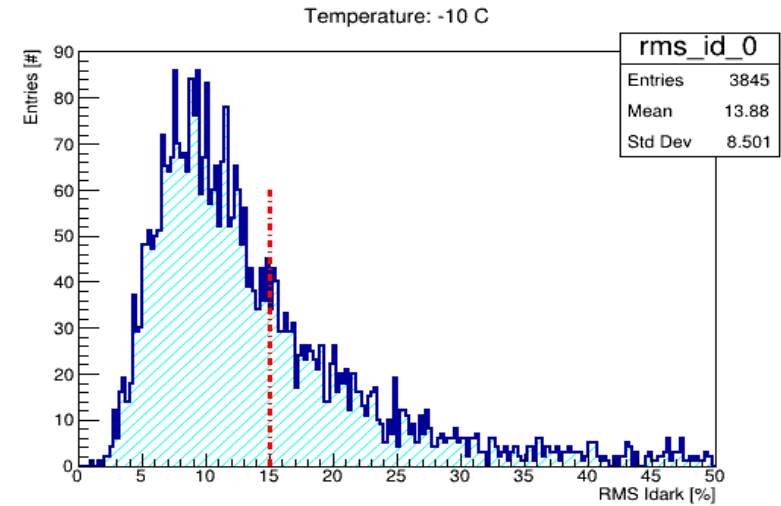
Temperature: 20 C



Temperature: 25 C

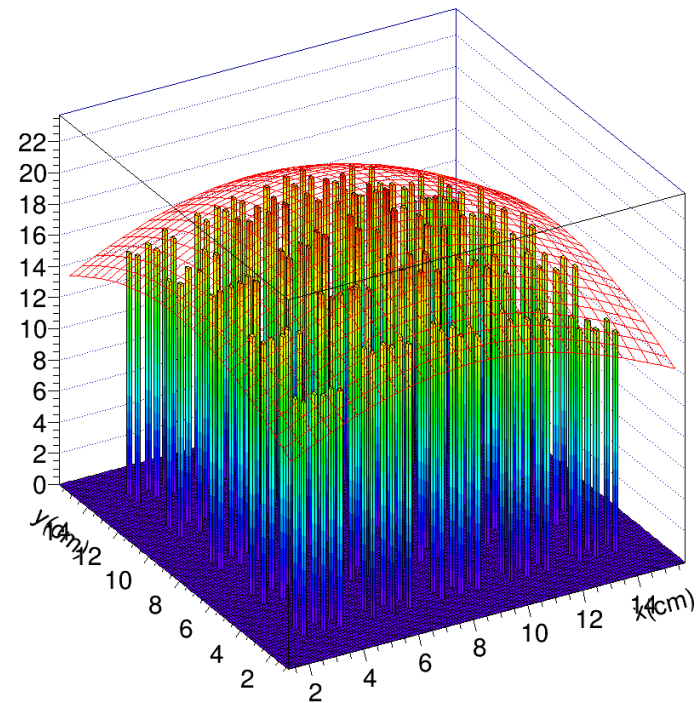
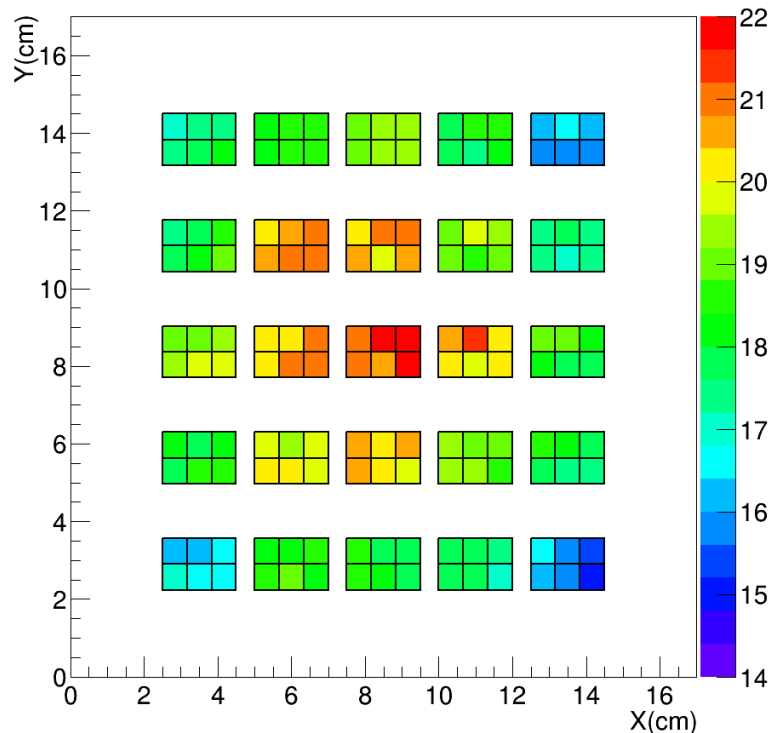


Dark Current RMS



Gain x PDE Measurement - Light Profile

- The light of the LED is not uniform on the sensors plate but has a gaussian profile:



- A good approximation of this profile has been obtained by fitting the current of the sensors biased at the operative voltage.. residuals have an **RMS ~ 4%**

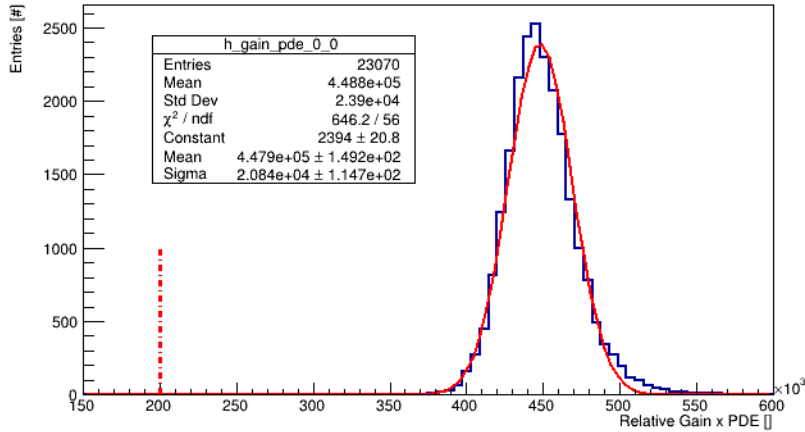
Gain x PDE

Refsens n.1, ID = 301

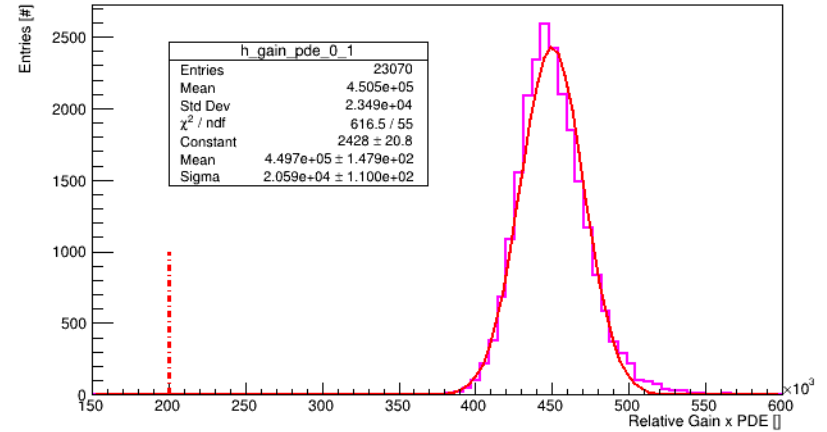
G x PDE ref = 4.e10⁵

$\sigma / \mu \sim 5\%$

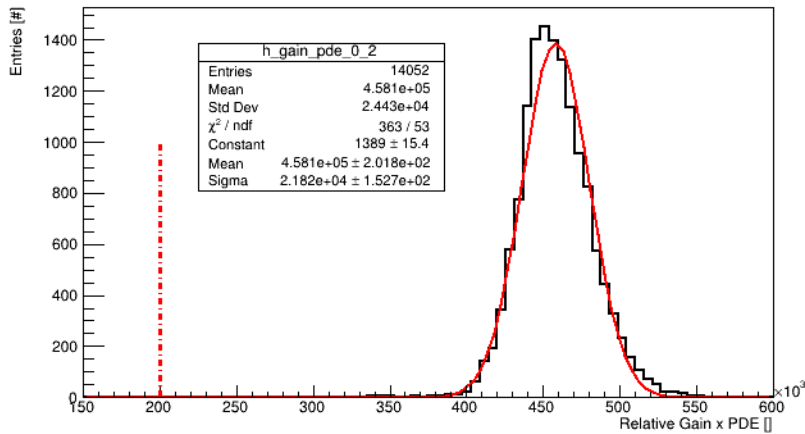
Ref 1 -Temperature -10 C



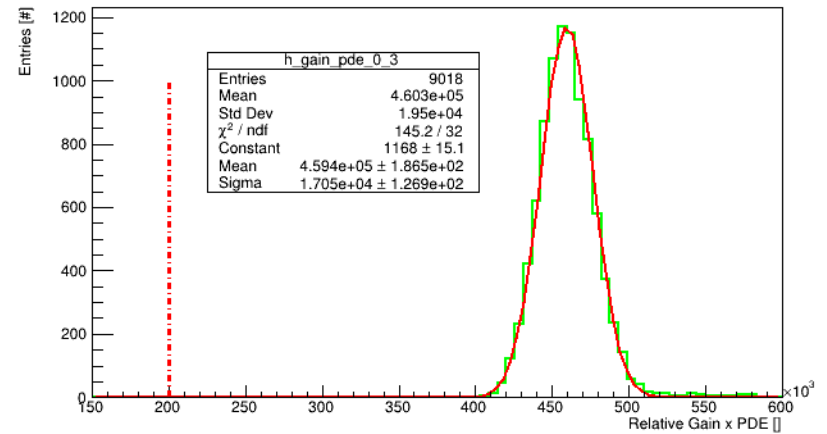
Ref 1 -Temperature 0 C



Ref 1 -Temperature 20 C



Ref 1 -Temperature 25 C



Conclusions

- The QA process for the Mu2e calorimeter Silicon PhotoMultipliers ended in June
- 14 batches have been tested for a total of 3875 photosensors
- 48 rejected sensors (about 1% of the total):
 - 26 for construction problem (dimensions, IV test failed..)
 - 22 for too large dark current RMS
- Photosensors ready for the assembly with FEE